

IRFB9N60APbF

HEXFET® Power MOSFET

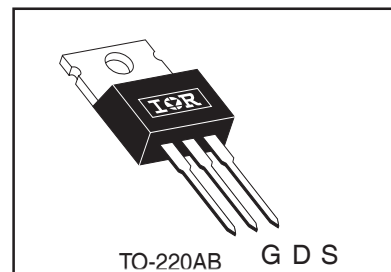
Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High speed power switching
- Lead-Free

Benefits

- Low Gate Charge Qg results in Simple Drive Requirement
- Improved Gate, Avalanche and dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current

V _{DSS}	R _{ds(on)} max	I _D
600V	0.75Ω	9.2A



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	9.2	A
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	5.8	
I _{DM}	Pulsed Drain Current ①	37	
P _D @ T _C = 25°C	Power Dissipation	170	W
	Linear Derating Factor	1.3	W/°C
V _{GS}	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T _J	Operating Junction and	-55 to + 150	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Applicable Off Line SMPS Topologies:

- Active Clamped Forward
- Main Switch

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Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	600	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.66	—	V/°C	Reference to 25°C , $I_D = 1\text{mA}$ ⑥
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.75	Ω	$V_{GS} = 10V, I_D = 5.5A$ ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	$V_{DS} = 600V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 480V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 30V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -30V$

Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	5.5	—	—	S	$V_{DS} = 50V, I_D = 5.5A$
Q_g	Total Gate Charge	—	—	49	nC	$I_D = 9.2A$
Q_{gs}	Gate-to-Source Charge	—	—	13		$V_{DS} = 400V$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	20		$V_{GS} = 10V$, See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	13	—	ns	$V_{DD} = 300V$
t_r	Rise Time	—	25	—		$I_D = 9.2A$
$t_{d(off)}$	Turn-Off Delay Time	—	30	—		$R_G = 9.1\Omega$
t_f	Fall Time	—	22	—		$R_D = 35.5\Omega$, See Fig. 10 ④
C_{iss}	Input Capacitance	—	1400	—	pF	$V_{GS} = 0V$
C_{oss}	Output Capacitance	—	180	—		$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	—	7.1	—		$f = 1.0\text{MHz}$, See Fig. 5
C_{oss}	Output Capacitance	—	1957	—		$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	49	—		$V_{GS} = 0V, V_{DS} = 480V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	96	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 480V$ ⑤

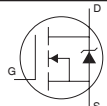
Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy②	—	290	mJ
I_{AR}	Avalanche Current①	—	9.2	A
E_{AR}	Repetitive Avalanche Energy①	—	17	mJ

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.75	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	62	

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	9.2	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	37		
V_{SD}	Diode Forward Voltage	—	—	1.5	V	$T_J = 25^\circ\text{C}, I_S = 9.2A, V_{GS} = 0V$ ④
t_{rr}	Reverse Recovery Time	—	530	800	ns	$T_J = 25^\circ\text{C}, I_F = 9.2A$
Q_{rr}	Reverse Recovery Charge	—	3.0	4.4	μC	$di/dt = 100A/\mu s$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$)				

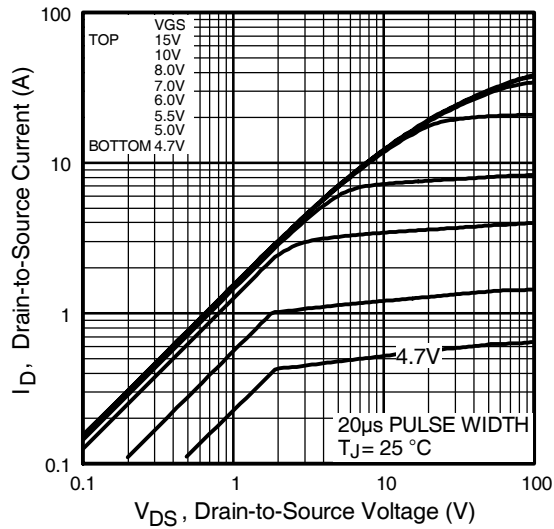


Fig 1. Typical Output Characteristics

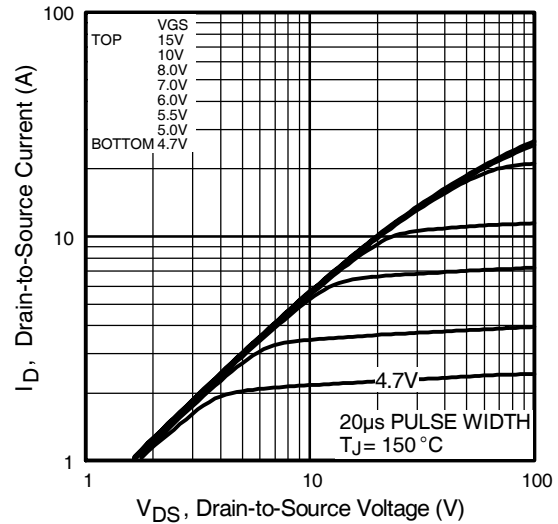


Fig 2. Typical Output Characteristics

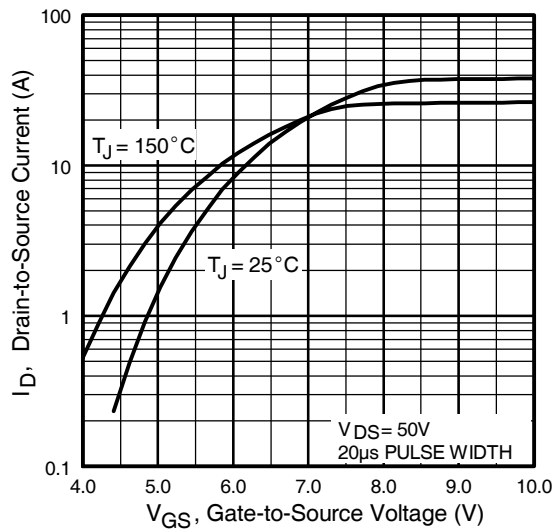


Fig 3. Typical Transfer Characteristics

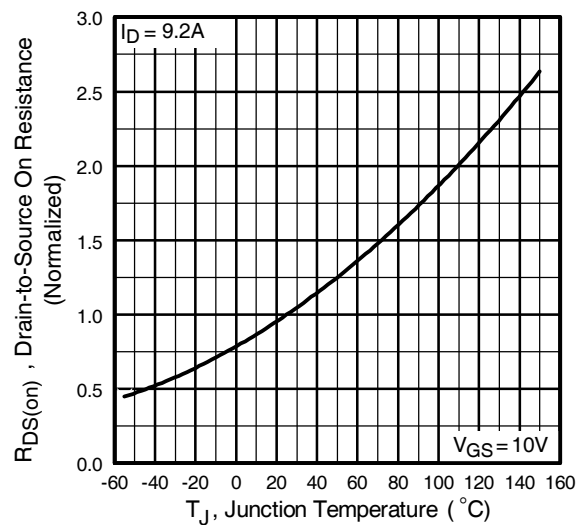


Fig 4. Normalized On-Resistance Vs. Temperature

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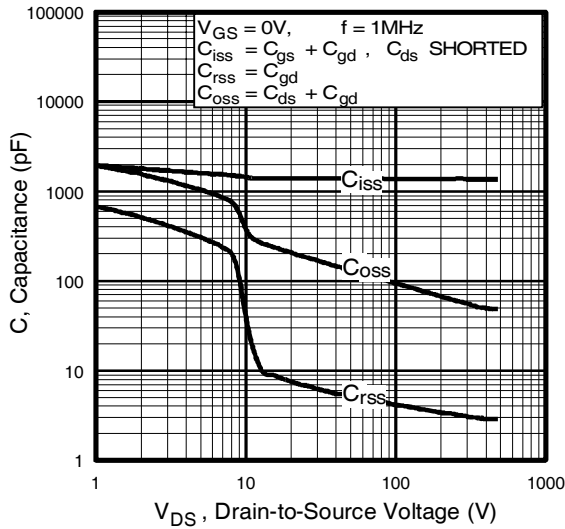


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

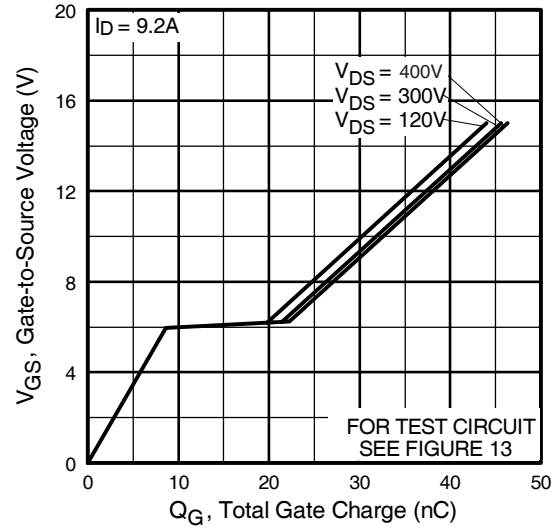


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

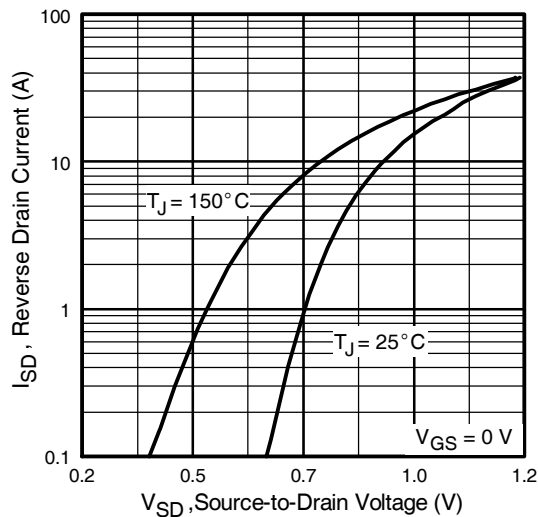


Fig 7. Typical Source-Drain Diode Forward Voltage

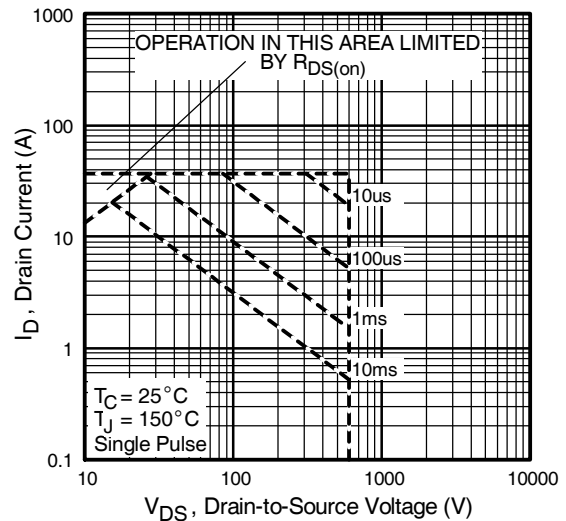


Fig 8. Maximum Safe Operating Area

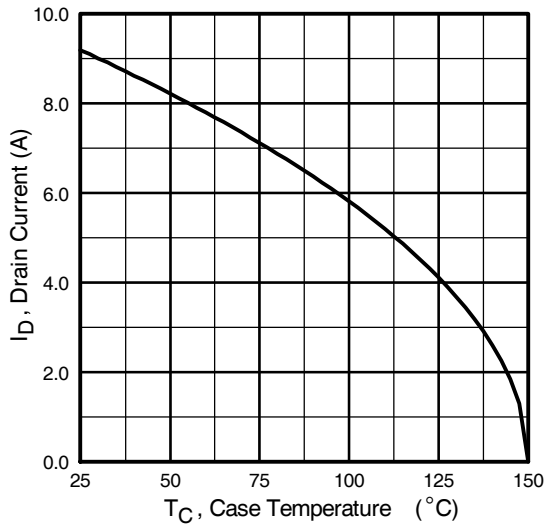


Fig 9. Maximum Drain Current Vs. Case Temperature

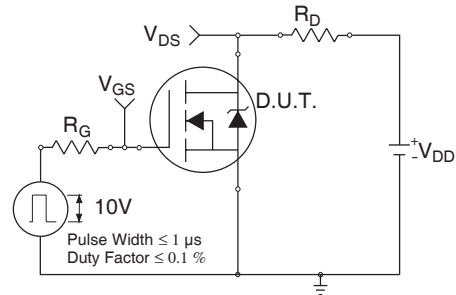


Fig 10a. Switching Time Test Circuit

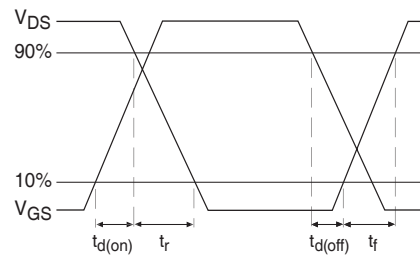


Fig 10b. Switching Time Waveforms

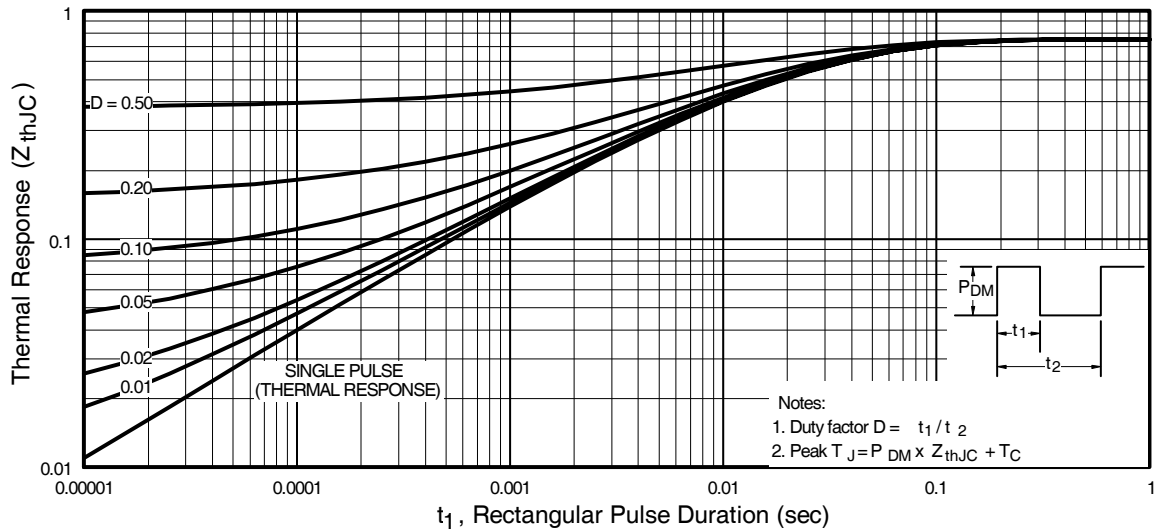


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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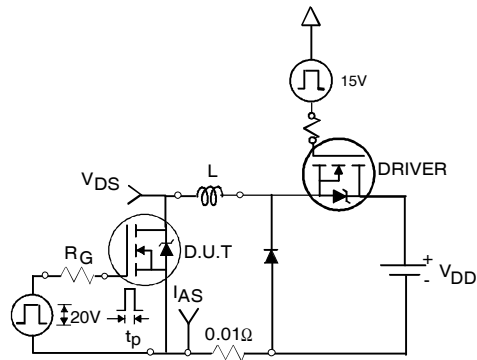


Fig 12a. Unclamped Inductive Test Circuit

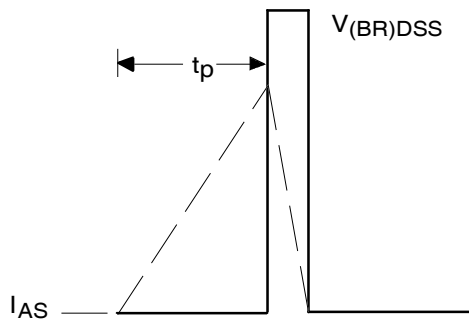


Fig 12b. Unclamped Inductive Waveforms

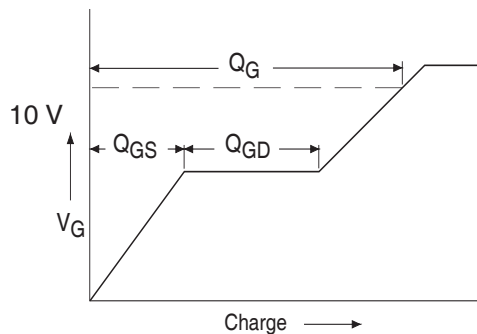


Fig 13a. Basic Gate Charge Waveform

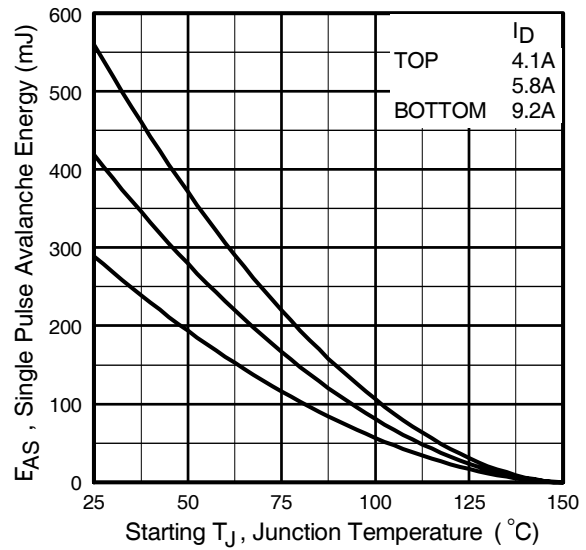


Fig 12c. Maximum Avalanche Energy
Vs. Drain Current

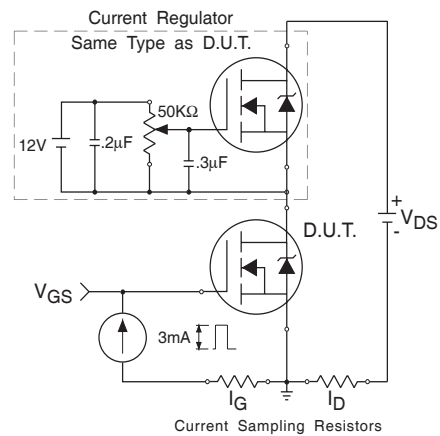


Fig 13b. Gate Charge Test Circuit

The diagram shows a Class D amplifier circuit. A square-wave voltage source (1) is connected to a gate resistor R_G and the gate of a MOSFET (D.U.T.). The MOSFET's source is grounded. Its drain is connected to a transformer (2) and a series combination of an inductor (3) and a load resistor (4). The other end of the load resistor is connected to ground. The transformer's secondary is also connected to ground. A dashed circle highlights the MOSFET and the inductor, with a note indicating low stray inductance, ground plane, and low leakage inductance. A list of layout considerations is provided: low stray inductance, ground plane, and low leakage inductance. A note states that the device is dv/dt controlled by R_G , the driver is the same type as the D.U.T., the source current I_{SD} is controlled by the duty factor 'D', and the D.U.T. is the device under test.

Circuit Layout Considerations

- Low Stray Inductance
- Ground Plane
- Low Leakage Inductance

Device Under Test (D.U.T.)

- dv/dt controlled by R_G
- Driver same type as D.U.T.
- I_{SD} controlled by Duty Factor "D"
- D.U.T. - Device Under Test

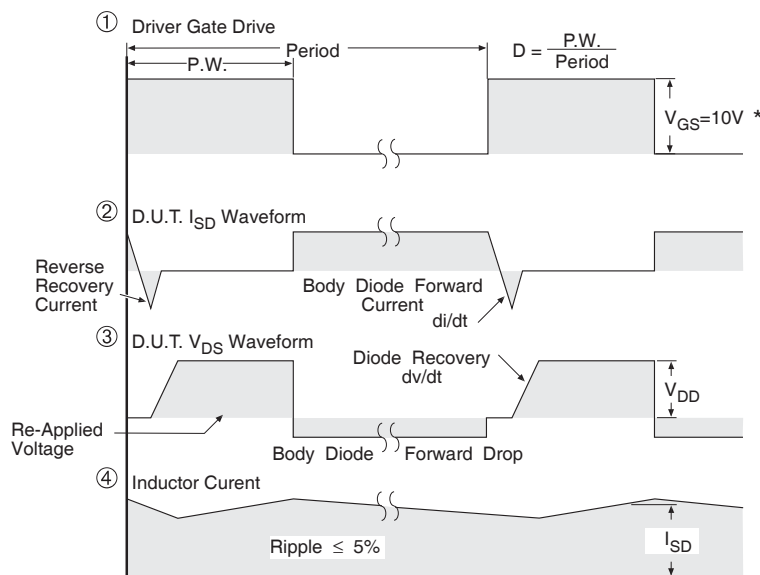
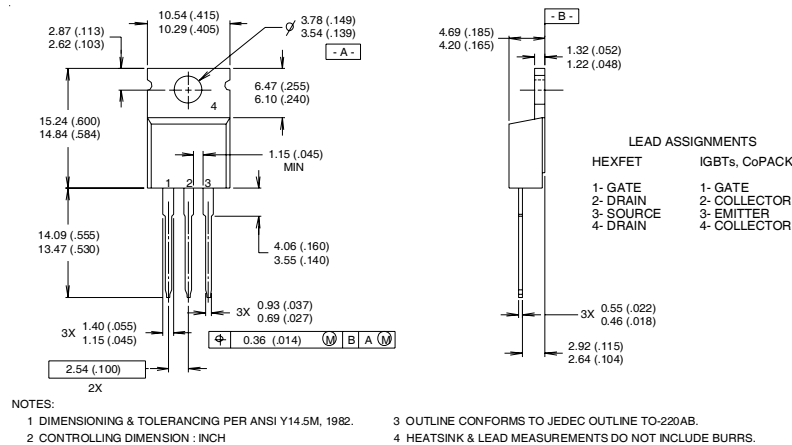


Fig 14. For N-Channel HEXFETS

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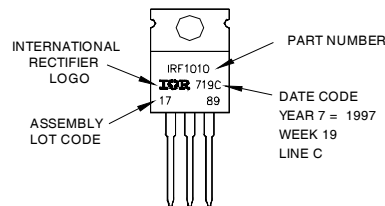
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TO-220AB Package Outline



TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"
Note: "P" in assembly line
position indicates "Lead-Free"



Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^\circ\text{C}$, $L = 6.8\text{mH}$
 $R_G = 25\Omega$, $I_{AS} = 9.2\text{A}$. (See Figure 12)
- ③ $I_{SD} \leq 9.2\text{A}$, $di/dt \leq 50\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$,
 $T_J \leq 150^\circ\text{C}$
- ④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.
- ⑤ C_{OSS} eff. is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 80% V_{DSS}

Data and specifications subject to change without notice.

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